



*Handwritten signature*  
PATENT  
1152-0263P

IN THE U.S. PATENT AND TRADEMARK OFFICE

*7/23  
ms12*

Applicant: Hideaki SAKAGUCHI Conf.: 4601  
Appl. No.: 09/624,014 Group: 2857  
Filed: July 21, 2000 Examiner: Mary C. BARAN  
For: TESTING DEVICE & TESTING METHOD FOR  
SEMICONDUCTOR INTEGRATED CIRCUITS

REPLY UNDER 37 C.F.R. § 1.111

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

RECEIVED  
JUL 11 2003  
TECHNOLOGY CENTER 2800  
July 2003

Sir:

In reply to the Office Action dated April 9, 2003, the following amendments and remarks are respectfully submitted in connection with the above-identified application.

This reply includes Claim Set as amended and Remarks.

The amendments presented herein comply with the "Revised Amendment Format" as set forth in the Official Gazette Notice dated February 25, 2003. In accordance with the Notice, the provisions of 37 C.F.R. § 1.121(a)-(d) are waived.